









ECE 595Z Digital VLSI Design Automation

Module 6 (Lectures 21-24): Timing Analysis and Optimization

Lecture 21



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Technology mapping: Re-cap

- Technology mapping is a DAG covering problem
 - Convert circuit to be mapped into subject graph, cells from library into pattern graphs
- Two solution approaches discussed
 - Binate covering formulation considers arbitrary
 DAGs, but not very scalable in practice
 - Tree covering using dynamic programming –
 divide DAG into trees, utilize optimal and efficient algorithm to map each tree
 - Inverter heuristic creates additional opportunities for matches, improves solution quality

Technology mapping: Remaining questions

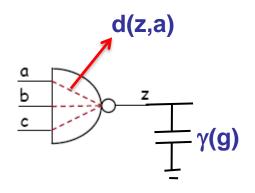
- How to map for minimum delay?
 - Not an additive cost function
 - Delay of a cell depends on its drivers and loads
- How to partition a DAG into trees

Technology Mapping for Delay

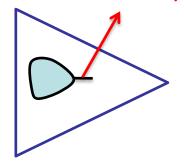
Delay of a gate

$$d(g,i) = \alpha(g,i) + \beta(g).\gamma(g)$$

- $\alpha(g,i)$: intrinsic delay of g from input i
- $-\beta(g)$: delay per unit load
- γ (g): capacitive load being driven
- Problem: In tree mapping,
 γ is NOT known when finding the best match at a vertex
 - γ is determined by matches at fanout



What is the value of γ ?



Technology Mapping for Delay: Constant Delay Model

- Simplification: Constant delay model
 - Delay of gate is independent of load it drives
- In this case, dynamic programming still works!

```
int min_delay_const_load(v, P){
/* v is a vertex in the tree, P is the set of pattern graphs */
         best_cost = infinity;
         foreach(m = match(v, P)) {
                   cost(m) = max_{v_i \in inputs(m)} (\alpha(m,i) + \beta(m) \gamma_0 +
                                       min_delay_constant_load(v<sub>i</sub>, P));
                   if(cost(m) < best_cost)
                            match(v) = m;
                            best_cost = cost(m);
         return best cost;
```

Technology Mapping for Delay: Load-dependent Delay Model

- Consider a set of discrete loads $\Gamma(v) = \{\gamma_1, \gamma_2, ..., \gamma_k\}$ for vertex v.
 - can be obtained by dividing useful range into bins
- Find best solution for each load at each vertex

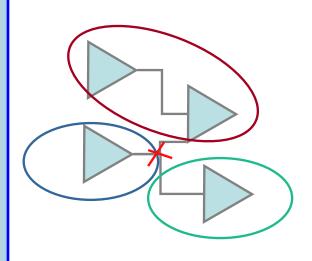
```
int min_delay(v, \Gamma(v), P){
                 for each (\gamma \in \Gamma(v))
                                    best cost(v, \gamma) = infinity;
                 foreach(m = match(v, P), \gamma \in \Gamma(v))
                                   cost(m, \gamma) = max<sub>v<sub>i</sub> ∈inputs(m)</sub> (\alpha(m,i) + \beta(m) \gamma + min_delay(v<sub>i</sub>, \gamma(m,i), P));

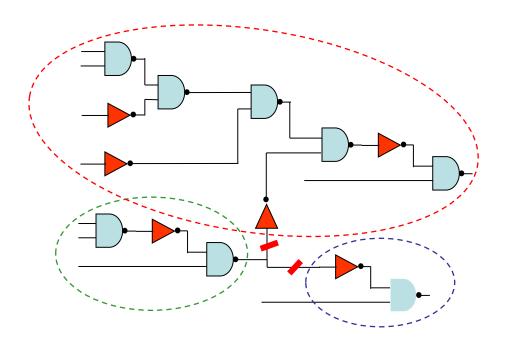
/* \gamma(m,i) is input capacitance of match m at input i */
                                   if(cost(m, \gamma) < best\_cost(v, \gamma)){
                                                     match(v, \gamma) = m;
                                                     best_cost(\dot{v}, \gamma) = cost(\dot{m}, \gamma);
                 return best_cost(v, \gamma_0);
```

• Final step: Given a load at the root of the tree, a backward traversal from the root to the leaves is needed at the end to pick the appropriate matches.

Partitioning a DAG into Trees

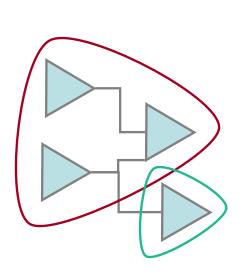
- Trivial Partition: Break the DAG at all multiple fanout points.
 - Guarantees no overlap among trees (no logic replication).
 - Sometimes leads to lots of small trees.

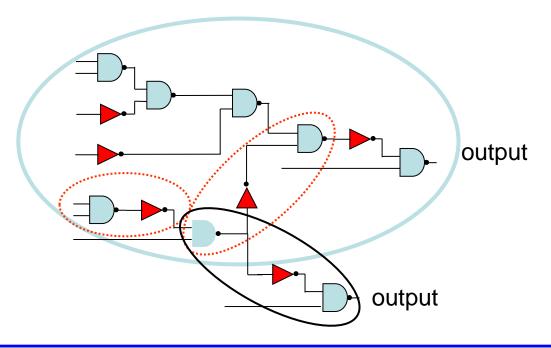




Partitioning a DAG into Trees

- Single-cone partition
 - From a single output, form a large tree back to the primary inputs;
 - Map successive outputs until they hit match output formed from mapping previous primary outputs.
 - Duplicates some logic (where trees overlap)
 - Produces larger trees, better area results in practice





Summary: Technology Mapping

- Three different approaches
 - Rule-based
 - Structural matching
 - Graph covering problem (subject DAG, pattern DAGs)
 - Binate covering formulation
 - » Too slow in practice
 - Tree covering
 - » Dynamic programming, very efficient and scalable
 - Boolean matching

General Principles

 Look for problems from a different domain that are equivalent to the problem you are trying to solve



- Technology mapping in logic synthesis ⇔ code generation in compilers
- Combining exact solutions for sub-problems may give an exact (or a good approximate) solution for the complete problem

Suggested Reading

- Hachtel & Somenzi, Chapter 13
- De Micheli, Chapter 10.1,10.2,10.3.1-10.3.3
- Key Papers
 - K. Keutzer, "DAGON: Technology binding and local optimization by DAG matching," in Proc. 24th ACM/IEEE Conf. on Design Automation, pp. 341-347, 1987
 - "MIS: A Multiple-Level Logic Optimization System", R. K.
 Brayton, R. Rudell, A. Sangiovanni-Vincentelli, A. R. Wang, IEEE
 Transactions on Computer-Aided Design of Integrated Circuits
 and Systems, vol. 6, no. 6, Nov. 1987, pp. 1062 1081
 - "Logic synthesis for VLSI design", R. Rudell, Ph.D. thesis, U. C. Berkeley, 1989.
 - Performance-Oriented Technology Mapping, (H.J. Touati, Ch.W. Moon and R. K. Brayton), Proceedings of MIT VLSI Conference, 1990.
 - "Technology mapping for low power", V. Tiwari, P. Ashar, and S. Malik, Design Automation Conference, pp. 74-79, 1993.

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Module 6 (Lectures 21-24): Timing Analysis and Optimization

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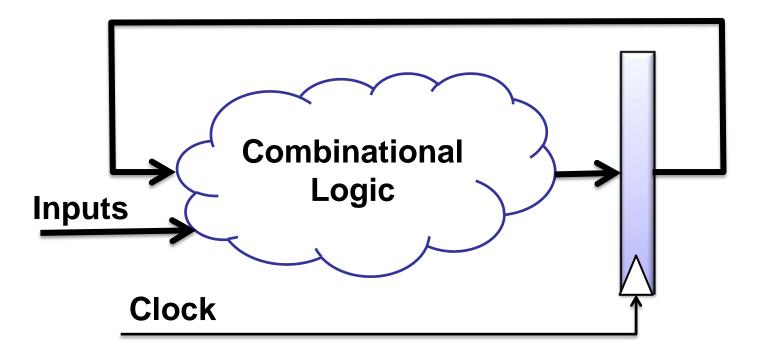
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Timing Optimization

- We have learnt thus far how to synthesize (small) circuits fast
- But, we also want to synthesize FAST circuits!
- Until recently, performance (clock frequency) was undisptued king for most ICs
 - Still is important, except power also matters in most applications and can be the primary metric in some

Timing Analysis

• Given a (sequential) circuit, how fast can I clock it while maintaining correct operation?



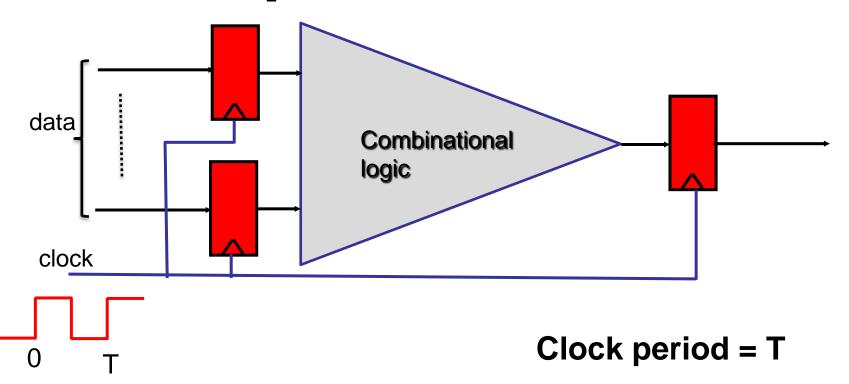
Outline

- Timing Analysis
 - Clocking criteria for sequential circuits
 - Timing graph
 - Delay models for gates
 - Topological timing analysis
 - Functional timing analysis
- Timing Optimization
 - Collapsing and re-structuring
 - Generalized Bypass Transform
 - Generalized Select Transform
 - Eliminating false paths



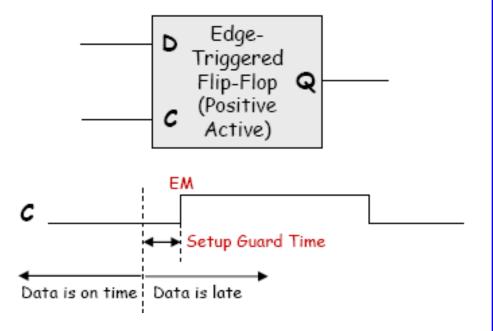
Clocking Criteria for Sequential Circuits

- Consider circuits with edge-triggered storage elements (Flip-Flops)
- What timing properties should be satisfied for correct operation?



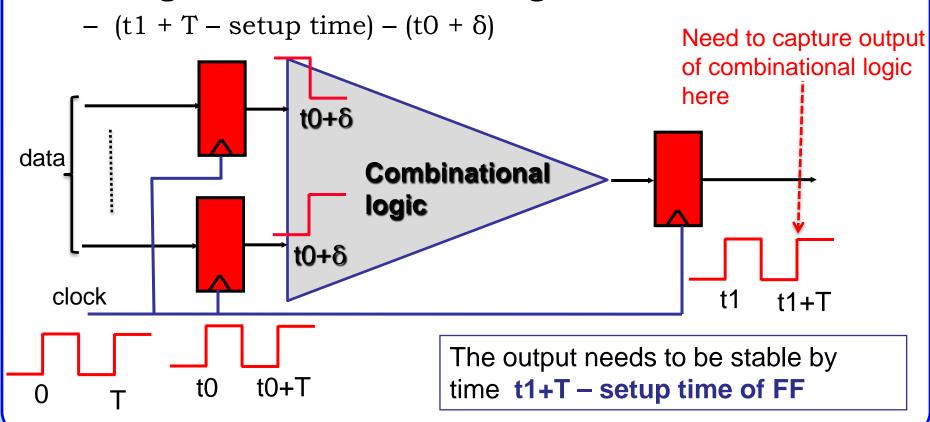
Setup Condition

Data that we intend to capture at a Flip-Flop must arrive before the clock edge by at least the setup time



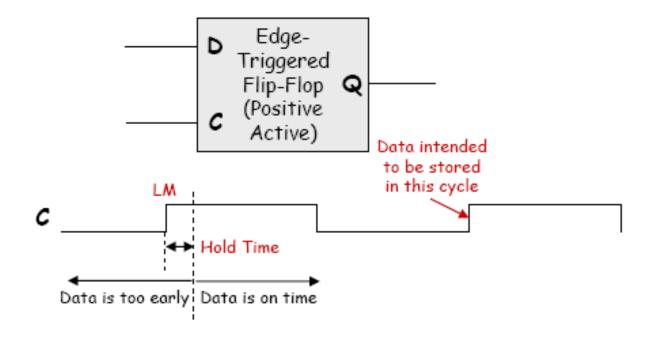
Setup Criterion for Sequential Circuits

- **Setup condition**: The outputs of the combinational logic should settle in time to be captured
- Translates to an upper bound on the longest delay through the combinational logic



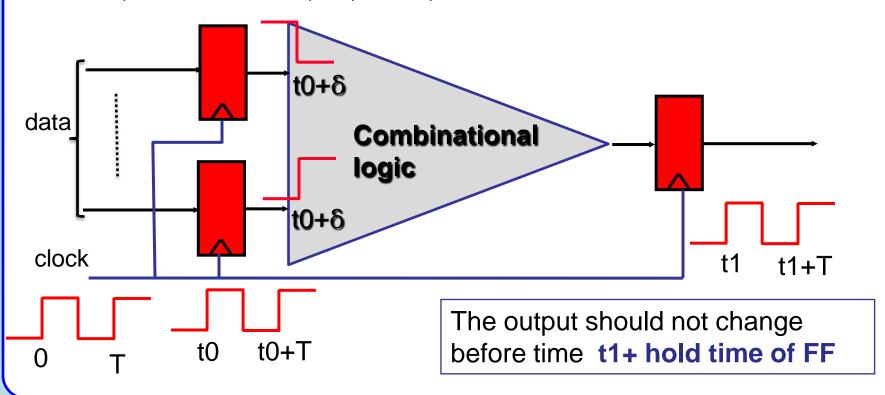
Hold Condition

 Data that we intend to capture at a Flip-Flop must not change after the clock edge until at least the hold time



Hold Criterion for Sequential Circuits

- **Hold condition**: The outputs of the combinational logic should not change too early
- Translates to a lower bound on the shortest delay through the combinational logic
 - (t1 + hold time) (t0 + δ)



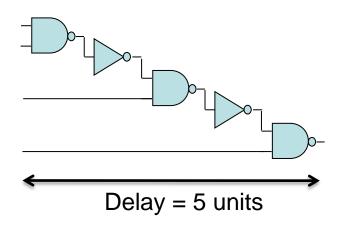
Delay Models for Gates

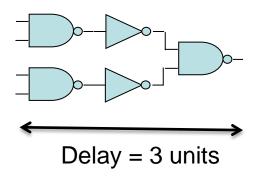
- Unit delay
- Constant delay
- Pin-to-pin delay
- State and Transition dependent delay
- Load and slew rate dependent delay
- PVT corners
- Statistical delay models

Accuracy vs. computation time tradeoff

Unit Delay Model

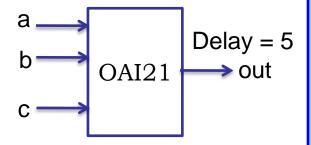
- Simplest model: Assume each gate has a fixed delay of 1 unit
- Usually applied to a network of 2-input gates and inverters
- Typically used in technologyindependent optimizations
- Still useful for coarsegrained comparisons between alternative circuit structures

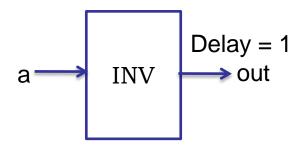




Constant Delay Model

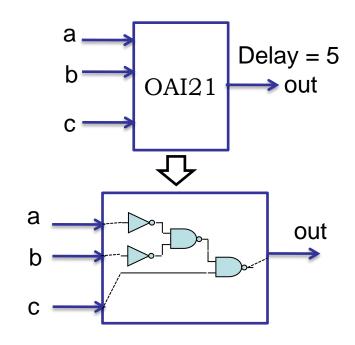
- Different but fixed delay for each gate type
- Simplest technologydependent delay model

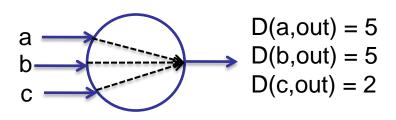




Pin-to-Pin Delay Model

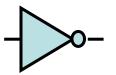
- Not all pins are created equal!
- Accounts for the fact that different paths through a gate can have different delays
- Input to output delay depends on transistor-level implementation of gate/cell



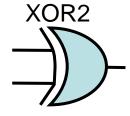


State / Transition Dependent Delay Model

- The values on inputs of the gate actually matter in determining its delay
 - Example: Not all transitions are equal!
 Rising and falling transition at output have different delays
- Note: Gate delay can be dependent on history



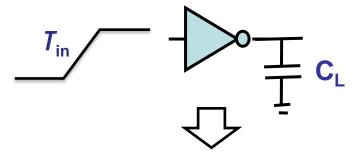
Delay(o/p rising) = 1.2 Delay(o/p falling) = 1



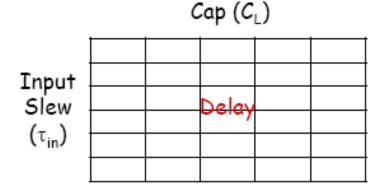
Delay(i/p falling, o/p falling) = 3.1 Delay(i/p falling, o/p rising) = 3.4 Delay(i/p rising, o/p falling) = 3.6 Delay(i/p rising, o/p rising) = 3.8

Load and Slew Rate Dependent Model

- Considers dependency of delay on output load and input slew rate
 - Lookup table with interpolation
 - Discretize useful range of input slew rates and output loads
 - Equation
 - Fit simulated / measured data
- Need similar model for computing slew rate at output



Delay table (o/p falling)



Delay equation (o/p falling)

Delay = $\alpha \cdot \tau_{in} + \beta \cdot C_L + \gamma \cdot \tau_{in} \cdot C_L + \delta$

PVT Corners

- Delay is impacted by Process, Voltage, and Temperature variations
- Conventional approach: Consider "corners"
 - Slow, Typical (or Nominal), Fast
- Problem: Increasing spread leads to very conservative estimates
 - Possible
 solution:
 Statistical
 models
 (active area
 of research)

	Progapation Delays			
	Path (I-O)	Perf. Level	Parameter	Delay V_{DD} =1.7V V_{DD} =1.8V V_{DD} =1.9V T_{j} =125°C T_{j} =0°C Process=Slow Process=Nom. Process=Fast
-	A-Z	Α	† _{PLH}	0.10+0.20N 0.09+0.19N 0.08+0.18N
	B-Z		† _{PHL} † _{PLH}	0.11+0.21N 0.10+0.18N 0.09+0.17N 0.09+0.19N 0.07+0.15N 0.06+0.14N
	A-Z	В	† _{PHL} † _{PLH}	0.08+0.17N 0.05+0.15N 0.04+0.12N

Summary

- Basic questions in timing analysis
 - Do the outputs of the combinational logic always reach the (final) stable value in time to be correctly captured?
 - Setup condition
 - Do the outputs of the combinational logic stay stable long enough to be correctly captured?
 - Hold condition
- Various delay models possible for gates
- Need delay models for wires too, but we will not talk about them in this class